Small Signal MOSFET

20 V, 540 mA / -20 V, -430 mA Complementary N- and P-Channel MOSFETs with Integrated Pull Up/Down Resistor and ESD Protection

Features

- Leading Trench Technology for Low RDS(on) Performance
- High Efficiency System Performance
- Low Threshold Voltage
- Integrated G-S Resistor on Both Devices
- ESD Protected Gate
- Small Footprint 1.6 x 1.6 mm
- These are Pb-Free Devices

Applications

- Load/Power Switching with Level Shift
- Portable Electronic Products such as GPS, Cell Phones, DSC, PMP, Bluetooth Accessories

MAXIMUM RATINGS (T_J = 25° C unless otherwise specified)

Para	Symbol	Value	Unit					
Drain-to-Source Voltaç	V _{DSS}	20	V					
Gate-to-Source Voltag	Gate-to-Source Voltage							
N-Channel Continu-	Steady	$T_A = 25^{\circ}C$		540				
ous Drain Current (Note 1)	State	$T_A = 85^{\circ}C$		390				
	t ≤ 5 s	$T_A = 25^{\circ}C$	1-	570	mA			
P-Channel Continu-	Steady	$T_A = 25^{\circ}C$	Ι _D	-430	mА			
ous Drain Current (Note 1)	State	$T_A = 85^{\circ}C$		-310				
	t ≤ 5 s	$T_A = 25^{\circ}C$		-455				
Power Dissipation	Steady	T _A = 25°C	PD	250				
(Note 1)	State				mW			
	$t \le 5 s$			280				
Pulsed Drain Current	N-Channel	t 10.00	1	1500	mA			
	P-Channel	t _p = 10 μs	IDM	-750	III/A			
Operating Junction and	perature	TJ,	-55 to 150	°C				
	T _{STG}	150						
Source Current (Body I	I _S	350	mA					
Lead Temperature for S (1/8" from case for 1	oses	ΤL	260	°C				

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

1. Surface-mounted on FR4 board using 1 in sq. pad size

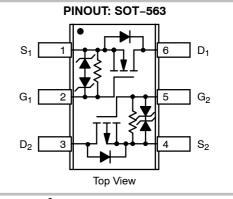
(Cu area = 1.127 in sq [1 oz] including traces).



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V _{(BR)DSS}	R _{DS(on)} Max	I _D Max (Note 1)
N-Channel 20 V	0.55 Ω @ 4.5 V	
	0.7 Ω @ 2.5 V	540 mA
	0.9 Ω @ 1.8 V	
	0.9 Ω @ –4.5 V	
P-Channel -20 V	1.2 Ω @ –2.5 V	–430 mA
	2.0 Ω @ –1.8 V	





ORDERING INFORMATION

Device	Package	Shipping [†]		
NTZD3156CT1G	SOT-563	4000 / Tape & Reel		
NTZD3156CT2G	SOT-563	4000 / Tape & Reel		
NTZD3156CT5G	SOT-563	8000 / Tape & Reel		

+For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

Thermal Resistance Ratings

Parameter	Symbol	Мах	Unit
Junction-to-Ambient - Steady State (Note 2)	$R_{ hetaJA}$	116	°C/W
Junction-to-Ambient – t = 5 s (Note 2)		304	

2. Surface mounted on FR4 board using 1 in sq pad size (Cu area = 1.127 in sq [1 oz] including traces).

ELECTRICAL CHARACTERISTICS (T_J = $25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	N/P	Test Condition		Min	Тур	Max	Unit	
OFF CHARACTERISTICS									
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	Ν	$V_{GS} = 0 V$	I _D = 250 μA	20			V	
		Р		I _D = -250 μA	-20				
Drain-to-Source Breakdown Voltage Temperature Coefficient	V(_{BR)DSS} /T _J			-		20		mV/°C	
Zero Gate Voltage Drain Current	I _{DSS}	Ν	V_{GS} = 0 V, V_{DS} = 16 V	$T_J = 25^{\circ}C$			1.0	μΑ	
		Р	$V_{GS} = 0 V, V_{DS} = -16 V$				-1.0		
		Ν	V_{GS} = 0 V, V_{DS} = 16 V	T _J = 125°C			2.0	μΑ	
		Р	$V_{GS} = 0 V, V_{DS} = -16V$				-5.0		
Gate-to-Source Leakage Current	I _{GSS}	Ν	V_{DS} = 0 V, V_{GS} = ±4.5 V				±50	μΑ	
		Р					±50		

ON CHARACTERISTICS (Note 3)

Gate Threshold Voltage	V _{GS(TH)}	Ν	$V_{GS} = V_{DS}$	I _D = 250 μA	0.45		1.0	V
		Р		I _D = -250 μA	-0.45		-1.0	
Gate Threshold Temperature Coefficient	V _{GS(TH)} /T _J					2.0		−mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	Ν	V_{GS} = 4.5 V, I _D =	V_{GS} = 4.5 V, I _D = 540 mA		0.19	0.55	
	P $V_{GS} = -4.5V, I_D = -430 \text{ mA}$		–430 mA		0.39	0.9		
		N $V_{GS} = 2.5 \text{ V}, \text{ I}_{D} = 500 \text{ mA}$		500 mA		0.26	0.7	
		Р	V_{GS} = -2.5V, I _D =	–300 mA		0.53	1.2	Ω
		Ν	V _{GS} = 1.8 V, I _D =	350 mA		0.36	0.9	
		Р	$V_{GS} = -1.8V, I_D =$	–150 mA		0.72	2.0	
Forward Transconductance	orward Transconductance g_{FS} N V_{DS} = 10 V, I_D = 5		540 mA		1.46		0	
		Р	V _{DS} = -10 V, I _D =	–430 mA	1.18			S

CHARGES, CAPACITANCES AND GATE RESISTANCE

Input Capacitance	C _{ISS}			72	
Output Capacitance	C _{OSS}	Ν	$f = 1 MHz, V_{GS} = 0 V$ $V_{DS} = 16 V$	13	
Reverse Transfer Capacitance	C _{RSS}			10	~ [
Input Capacitance	C _{ISS}			93	pF
Output Capacitance	C _{OSS}	Р	f = 1 MHz, V _{GS} = 0 V V _{DS} = -16 V	15	
Reverse Transfer Capacitance	C _{RSS}		20	11	

3. Pulse Test: pulse width \leq 300 $\mu s,$ duty cycle \leq 2%

ELECTRICAL CHARACTERISTICS (T_J = 25° C unless otherwise specified)

Parameter	Symbol	N/P	Test Condition	Min	Тур	Max	Unit
CHARGES, CAPACITANCES	AND GATE RE	SISTAN	CE				
Total Gate Charge	Q _{G(TOT)}				1.39	2.5	
Threshold Gate Charge	Q _{G(TH)}	N			0.1		
Gate-to-Source Charge	Q _{GS}		V _{GS} = 4.5 V, V _{DS} = 10 V; I _D = 540 mA		0.26		
Gate-to-Drain Charge	Q _{GD}				0.39		
Total Gate Charge	Q _{G(TOT)}				1.49	2.5	nC
Threshold Gate Charge	Q _{G(TH)}	Р	V_{GS} = -4.5 V, V_{DS} = -10 V; I_{D} = -430 mA		0.1		
Gate-to-Source Charge	Q _{GS}	Р			0.3		
Gate-to-Drain Charge	Q _{GD}				0.37		
SWITCHING CHARACTERIS	TICS (V _{GS} = V)	(Note 4)		-	-	-
Turn–On Delay Time	t _{d(ON)}	Ν			7.7		
Rise Time	t _r		V _{GS} = 4.5 V, V _{DD} = 10 V, I _D = 540 mA,		5.3		
Turn-Off Delay Time	t _{d(OFF)}		$R_{G} = 10 \Omega$		21		
Fall Time	t _f				10		
Turn–On Delay Time	t _{d(ON)}	Р			9.2		ns
Rise Time	t _r		V _{GS} = -4.5 V, V _{DD} = -10 V, I _D = -430 mA,		6.5		
Turn-Off Delay Time	t _{d(OFF)}	1	$R_{G} = 10 \Omega$		29		

Drain-Source Diode Characteristics

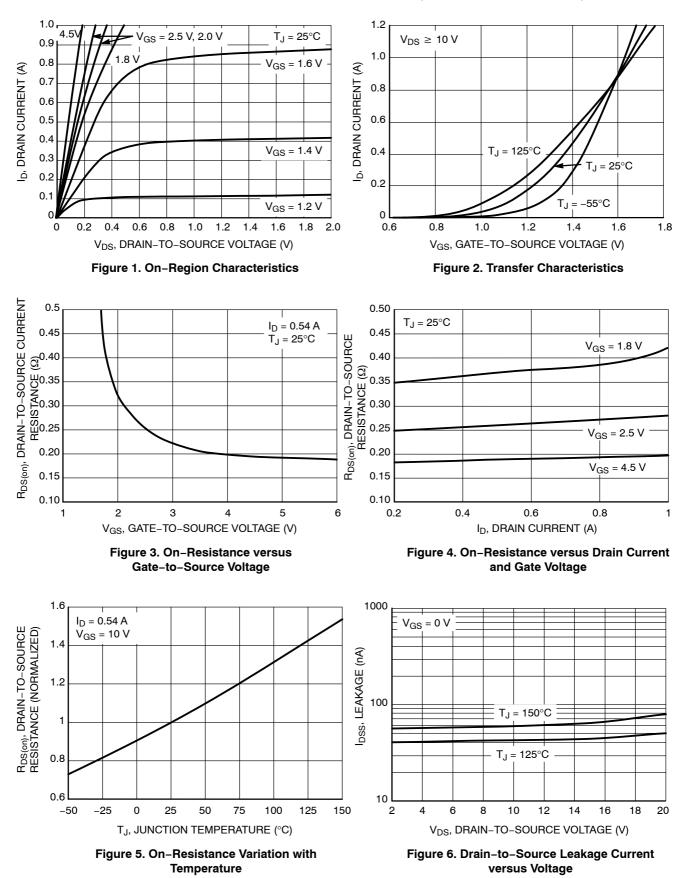
Fall Time

Forward Diode Voltage	V _{SD}	Ν		I _S = 350 mA	0.77	1.2	
		Р	V_{GS} = 0 V, T _J = 25°C	I _S = -350 mA	-0.77	-1.2	V
		Ν	V 0.V T 105%C	I _S = 350 mA	0.65		v
		Р	V _{GS} = 0 V, T _J = 125°C	I _S = -350 mA	0.63		
Reverse Recovery Time	t _{RR}	Ν	$V_{GS} = 0 V,$	I _S = 350 mA	9.4		20
		Р	dIS/dt = 100 A/µs	I _S = -350 mA	14.6		ns

19.5

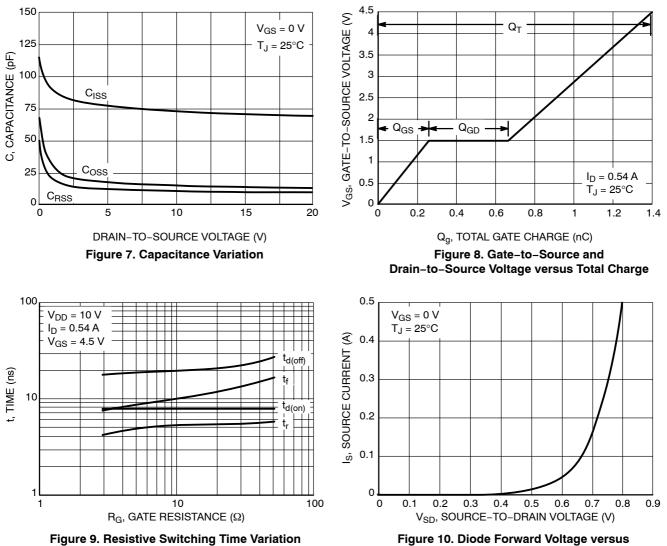
4. Switching characteristics are independent of operating junction temperatures

t_f



N-CHANNEL TYPICAL PERFORMANCE CURVES (T_J = 25°C unless otherwise noted)

N-CHANNEL TYPICAL PERFORMANCE CURVES ($T_J = 25^{\circ}C$ unless otherwise noted)

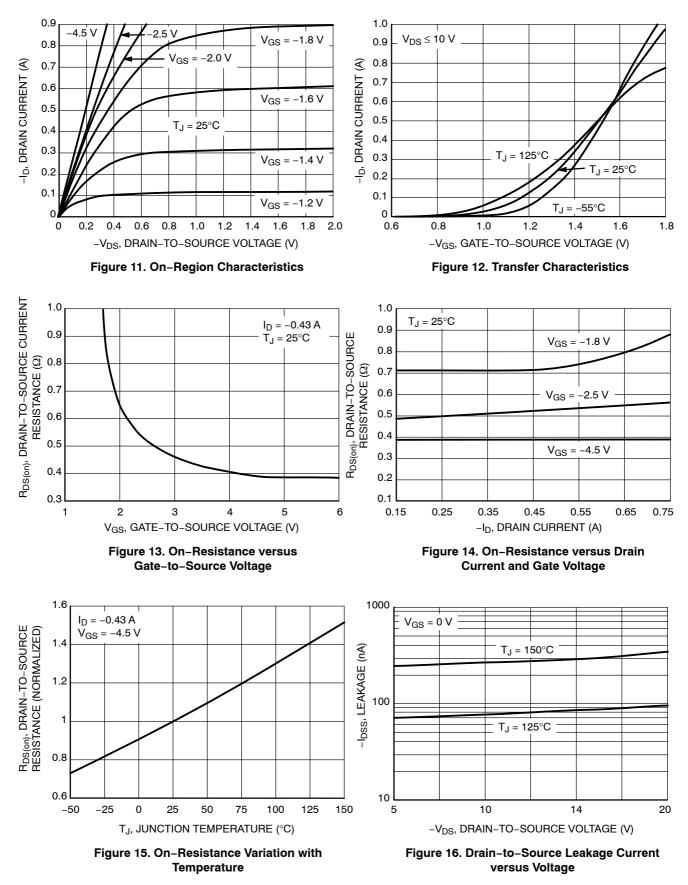


Current

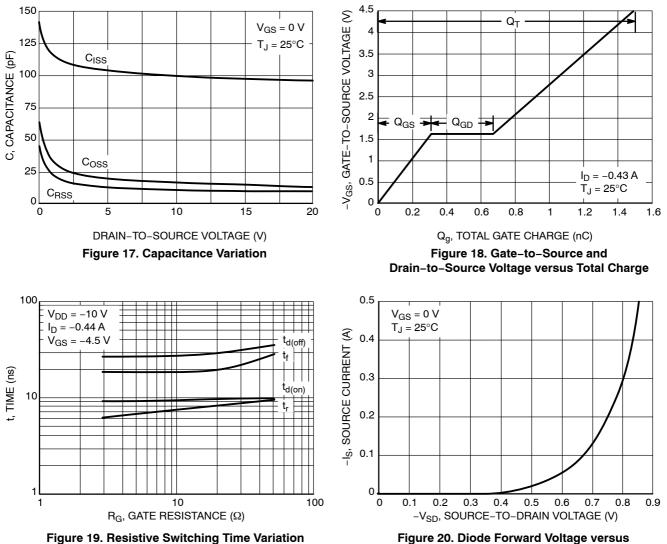
versus Gate Resistance

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P-CHANNEL TYPICAL PERFORMANCE CURVES (T_J = 25°C unless otherwise noted)



P-CHANNEL TYPICAL PERFORMANCE CURVES ($T_J = 25^{\circ}C$ unless otherwise noted)



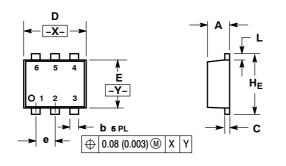
versus Gate Resistance

Figure 20. Diode Forward Voltage versus Current

PACKAGE DIMENSIONS

SOT-563, 6 LEAD

CASE 463A-01 ISSUE F



NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ANSI
- Y14.5M, 1982 2
- CONTROLLING DIMENSION: MILLIMETERS MAXIMUM LEAD THICKNESS INCLUDES LEAD З.

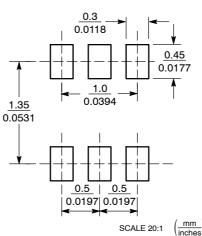
FINISH THICKNESS. MINIMUM LEAD THICKNESS IS THE MINIMUM THICKNESS OF BASE MATERIAL.

	MIL	LIMETE	RS	INCHES			
DIM	MIN	NOM	MAX	MIN	NOM	MAX	
Α	0.50	0.55	0.60	0.020	0.021	0.023	
b	0.17	0.22	0.27	0.007	0.009	0.011	
С	0.08	0.12	0.18	0.003	0.005	0.007	
D	1.50	1.60	1.70	0.059	0.062	0.066	
Е	1.10	1.20	1.30	0.043	0.047	0.051	
е		0.5 BSC)	0	.02 BSC)	
L	0.10	0.20	0.30	0.004	0.008	0.012	
HE	1.50	1.60	1.70	0.059	0.062	0.066	

STYLE 9: PIN 1. SOURCE 1 2. GATE 1 3. DRAIN 2 4. SOURCE 2 GATE 2 5.

6. DRAIN 1

SOLDERING FOOTPRINT*



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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